



Welcome to [E-XFL.COM](https://www.e-xfl.com)

Understanding **Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	5712
Number of Logic Elements/Cells	57120
Total RAM Bits	5215104
Number of I/O	1022
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1508-BBGA, FCBGA
Supplier Device Package	1508-FBGA, FC (40x40)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1s60f1508c6

DSP Block Interface	2-70
PLLs & Clock Networks	2-73
Global & Hierarchical Clocking	2-73
Enhanced & Fast PLLs	2-81
Enhanced PLLs	2-87
Fast PLLs	2-100
I/O Structure	2-104
Double-Data Rate I/O Pins	2-111
External RAM Interfacing	2-115
Programmable Drive Strength	2-119
Open-Drain Output	2-120
Slew-Rate Control	2-120
Bus Hold	2-121
Programmable Pull-Up Resistor	2-122
Advanced I/O Standard Support	2-122
Differential On-Chip Termination	2-127
MultiVolt I/O Interface	2-129
High-Speed Differential I/O Support	2-130
Dedicated Circuitry	2-137
Byte Alignment	2-140
Power Sequencing & Hot Socketing	2-140

Chapter 3. Configuration & Testing

IEEE Std. 1149.1 (JTAG) Boundary-Scan Support	3-1
SignalTap II Embedded Logic Analyzer	3-5
Configuration	3-5
Operating Modes	3-5
Configuring Stratix FPGAs with JRunner	3-7
Configuration Schemes	3-7
Partial Reconfiguration	3-7
Remote Update Configuration Modes	3-8
Stratix Automated Single Event Upset (SEU) Detection	3-12
Custom-Built Circuitry	3-13
Software Interface	3-13
Temperature Sensing Diode	3-13

Chapter 4. DC & Switching Characteristics

Operating Conditions	4-1
Power Consumption	4-17
Timing Model	4-19
Preliminary & Final Timing	4-19
Performance	4-20
Internal Timing Parameters	4-22
External Timing Parameters	4-33
Stratix External I/O Timing	4-36
I/O Timing Measurement Methodology	4-60
External I/O Delay Parameters	4-66

Chapter	Date/Version	Changes Made
4		- Table 4–48 on page 4–30: added rows $t_{M512CLKSENSU}$ and $t_{M512CLKENH}$, and updated symbol names. - Updated power-up current (ICCINT) required to power a Stratix device on page 4–17. - Updated Table 4–37 on page 4–22 through Table 4–43 on page 4–27. - Table 4–49 on page 4–31: added rows $t_{M4KCLKENSU}$, $t_{M4KCLKENH}$, $t_{M4KBESU}$, and t_{M4KBEH}, deleted rows $t_{M4KRADDRASU}$ and $t_{M4KRADDRH}$, and updated symbol names. - Table 4–50 on page 4–31: added rows $t_{MRAMCLKENSU}$, $t_{MRAMCLKENH}$, $t_{MRAMBESU}$, and $t_{MRAMBEH}$, deleted rows $t_{MRAMADDRASU}$ and $t_{MRAMADDRH}$, and updated symbol names. - Table 4–52 on page 4–34: updated table, deleted “Conditions” column, and added rows t_{XZ} and t_{ZX}. - Table 4–52 on page 4–34: updated table, deleted “Conditions” column, and added rows t_{XZ} and t_{ZX}. - Table 4–53 on page 4–34: updated table and added rows t_{XZPLL} and t_{ZXPLL}. - Updated Note 2 in Table 4–53 on page 4–34. - Table 4–54 on page 4–35: updated table, deleted “Conditions” column, and added rows t_{XZPLL} and t_{ZXPLL}. - Updated Note 2 in Table 4–54 on page 4–35. - Deleted Note 2 from Table 4–55 on page 4–36 through Table 4–66 on page 4–41. - Updated Table 4–55 on page 4–36 through Table 4–96 on page 4–56. Added rows T_{XZ}, T_{ZX}, T_{XZPLL}, and T_{ZXPLL}. - Added Note 4 to Table 4–101 on page 4–62. - Deleted Note 1 from Table 4–67 on page 4–42 through Table 4–84 on page 4–50. - Added new section “I/O Timing Measurement Methodology” on page 4–60. - Deleted Note 1 from Table 4–67 on page 4–42 through Table 4–84 on page 4–50. - Deleted Note 2 from Table 4–85 on page 4–51 through Table 4–96 on page 4–56. - Added Note 4 to Table 4–101 on page 4–62. - Table 4–102 on page 4–64: updated table and added Note 4. - Updated description of “External I/O Delay Parameters” on page 4–66. - Added Note 1 to Table 4–109 on page 4–73 and Table 4–110 on page 4–74. - Updated Table 4–103 on page 4–66 through Table 4–110 on page 4–74. - Deleted Note 2 from Table 4–103 on page 4–66 through Table 4–106 on page 4–69. - Added new paragraph about output adder delays on page 4–68. - Updated Table 4–110 on page 4–74. - Added Note 1 to Table 4–111 through Table 4–113 on page 4–75.

M512 RAM Block

The M512 RAM block is a simple dual-port memory block and is useful for implementing small FIFO buffers, DSP, and clock domain transfer applications. Each block contains 576 RAM bits (including parity bits). M512 RAM blocks can be configured in the following modes:

- Simple dual-port RAM
- Single-port RAM
- FIFO
- ROM
- Shift register

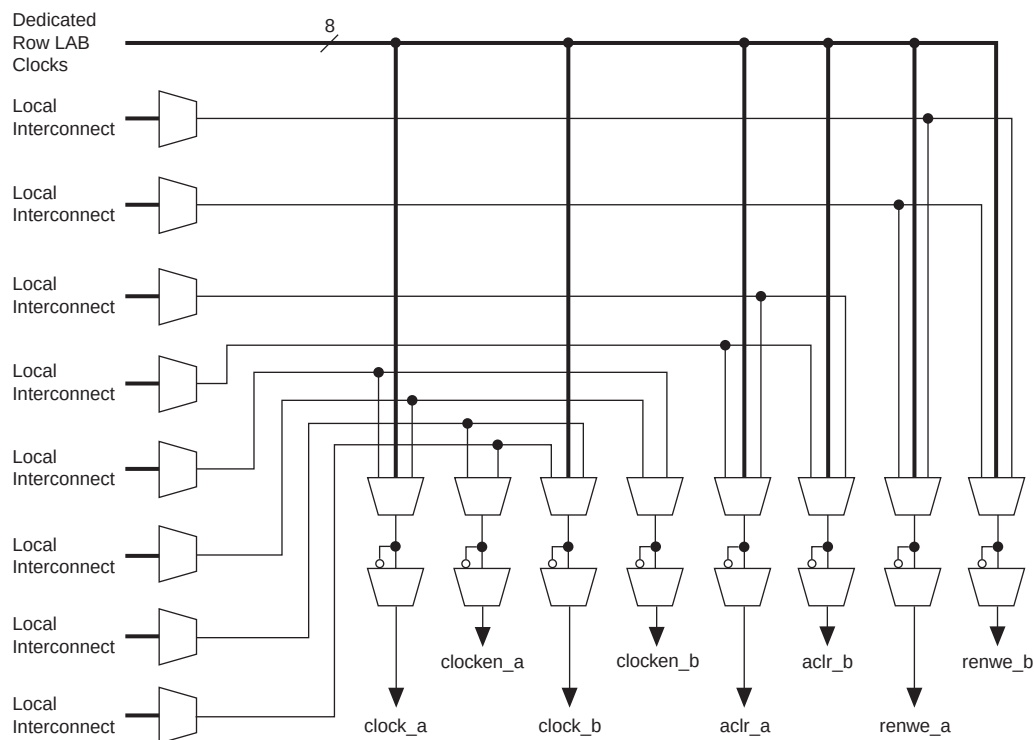
When configured as RAM or ROM, you can use an initialization file to pre-load the memory contents.

The memory address depths and output widths can be configured as 512×1 , 256×2 , 128×4 , 64×8 (64×9 bits with parity), and 32×16 (32×18 bits with parity). Mixed-width configurations are also possible, allowing different read and write widths. [Table 2–4](#) summarizes the possible M512 RAM block configurations.

Table 2–4. M512 RAM Block Configurations (Simple Dual-Port RAM)							
Read Port	Write Port						
	512×1	256×2	128×4	64×8	32×16	64×9	32×18
512×1	✓	✓	✓	✓	✓		
256×2	✓	✓	✓	✓	✓		
128×4	✓	✓	✓		✓		
64×8	✓	✓		✓			
32×16	✓	✓	✓		✓		
64×9						✓	
32×18							✓

When the M512 RAM block is configured as a shift register block, a shift register of size up to 576 bits is possible.

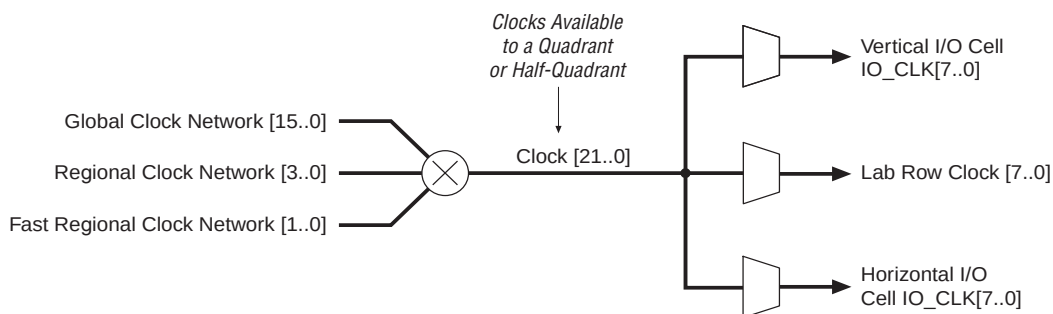
The M512 RAM block can also be configured to support serializer and deserializer applications. By using the mixed-width support in combination with DDR I/O standards, the block can function as a SERDES to support low-speed serial I/O standards using global or regional clocks. See [“I/O Structure” on page 2–104](#) for details on dedicated SERDES in Stratix devices.

Figure 2–19. M-RAM Block Control Signals

One of the M-RAM block's horizontal sides drive the address and control signal (clock, renwe, byteena, etc.) inputs. Typically, the horizontal side closest to the device perimeter contains the interfaces. The one exception is when two M-RAM blocks are paired next to each other. In this case, the side of the M-RAM block opposite the common side of the two blocks contains the input interface. The top and bottom sides of any M-RAM block contain data input and output interfaces to the logic array. The top side has 72 data inputs and 72 data outputs for port B, and the bottom side has another 72 data inputs and 72 data outputs for port A. [Figure 2–20](#) shows an example floorplan for the EP1S60 device and the location of the M-RAM interfaces.

Input/Output Clock Mode

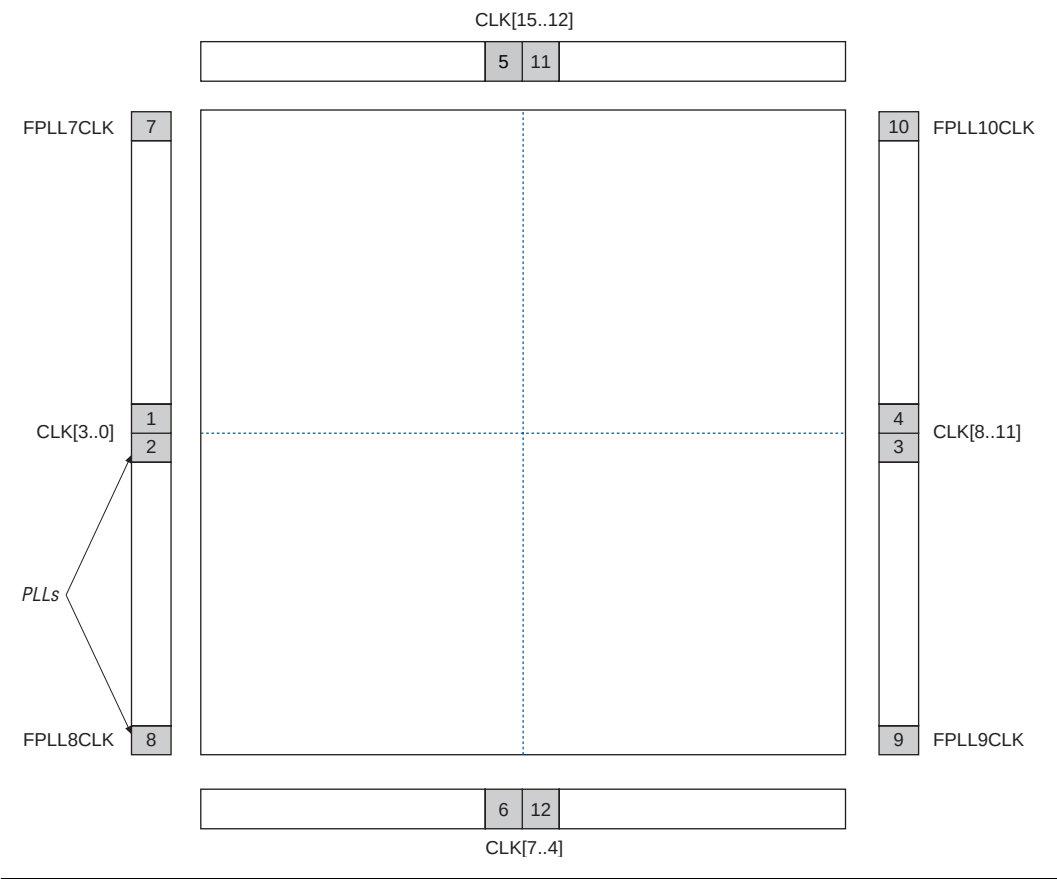
Input/output clock mode can be implemented for both the true and simple dual-port memory modes. On each of the two ports, A or B, one clock controls all registers for inputs into the memory block: data input, `wren`, and address. The other clock controls the block's data output registers. Each memory block port, A or B, also supports independent clock enables and asynchronous clear signals for input and output registers. [Figures 2–25](#) and [2–26](#) show the memory block in input/output clock mode.

Figure 2–46. Regional Clock Bus

IOE clocks have horizontal and vertical block regions that are clocked by eight I/O clock signals chosen from the 22 quadrant or half-quadrant clock resources. [Figures 2–47](#) and [2–48](#) show the quadrant and half-quadrant relationship to the I/O clock regions, respectively. The vertical regions (column pins) have less clock delay than the horizontal regions (row pins).

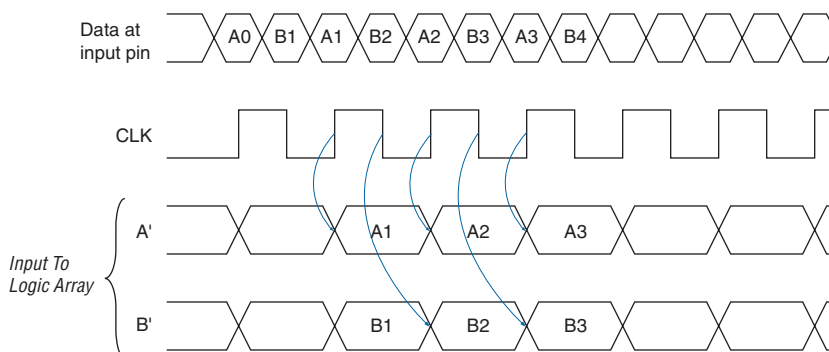
Figure 2–49 shows a top-level diagram of the Stratix device and PLL floorplan.

Figure 2–49. PLL Locations

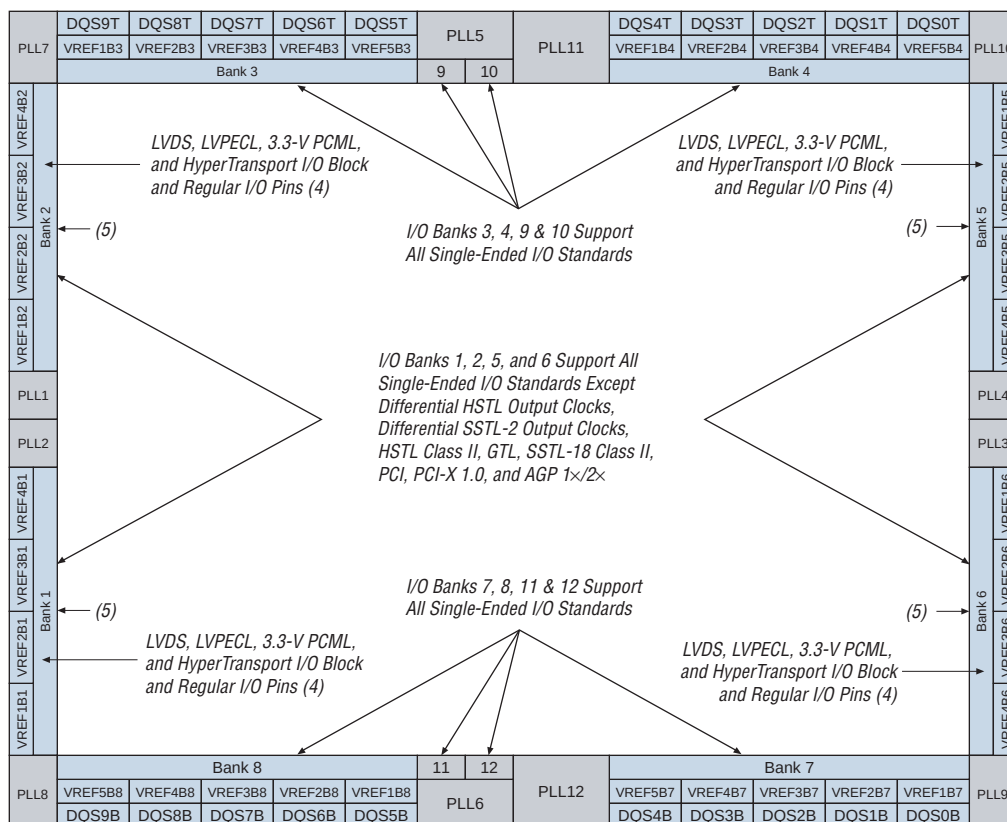




- (1) The 16 control signals are composed of four output enables `io_boe[3..0]`, four clock enables `io_bce[3..0]`, four clocks `io_bclk[3..0]`, and four clear signals `io_bclr[3..0]`.
- (2) The 42 data and control signals consist of 12 data out lines; six lines each for DDR applications `io_dataouta[5..0]` and `io_dataoutb[5..0]`, six output enables `io_coe[5..0]`, six input clock enables `io_cce_in[5..0]`, six output clock enables `io_cce_out[5..0]`, six clocks `io_cclk[5..0]`, and six clear signals `io_cclr[5..0]`.

Figure 2–66. Input Timing Diagram in DDR Mode

When using the IOE for DDR outputs, the two output registers are configured to clock two data paths from LEs on rising clock edges. These output registers are multiplexed by the clock to drive the output pin at a $\times 2$ rate. One output register clocks the first bit out on the clock high time, while the other output register clocks the second bit out on the clock low time. [Figure 2–67](#) shows the IOE configured for DDR output. [Figure 2–68](#) shows the DDR output timing diagram.

Figure 2–70. Stratix I/O Banks *Notes (1), (2), (3)***Notes to Figure 2–70:**

- (1) Figure 2–70 is a top view of the silicon die. This will correspond to a top-down view for non-flip-chip packages, but will be a reverse view for flip-chip packages.
- (2) Figure 2–70 is a graphic representation only. See the device pin-outs on the web (www.altera.com) and the Quartus II software for exact locations.
- (3) Banks 9 through 12 are enhanced PLL external clock output banks.
- (4) If the high-speed differential I/O pins are not used for high-speed differential signaling, they can support all of the I/O standards except HSTL Class I and II, GTL, SSTL-18 Class II, PCI, PCI-X 1.0, and AGP 1x/2x.
- (5) For guidelines for placing single-ended I/O pads next to differential I/O pads, see the *Selectable I/O Standards in Stratix and Stratix GX Devices* chapter in the *Stratix Device Handbook, Volume 2*.

Table 2–40. EP1S60 Differential Channels (Part 2 of 2) Note (1)

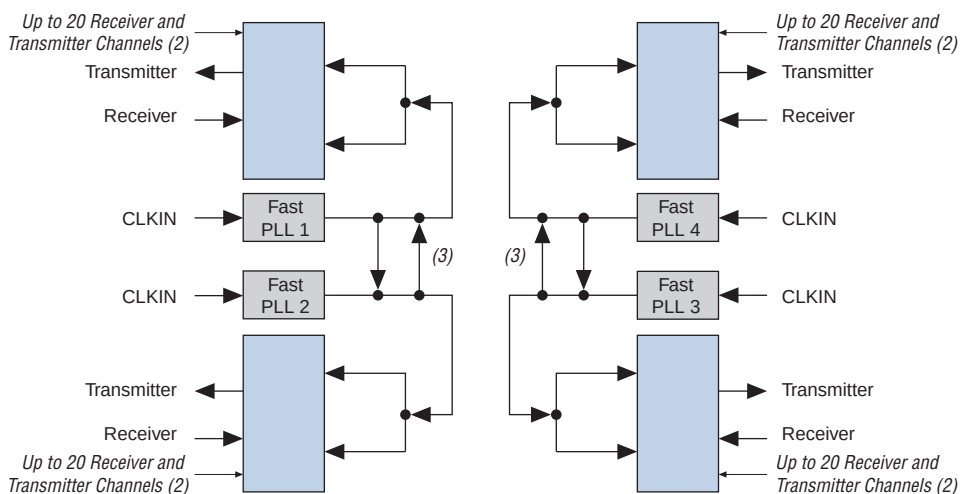
Package	Transmitter/ Receiver	Total Channels	Maximum Speed (Mbps)	Center Fast PLLs				Corner Fast PLLs (2), (3)			
				PLL1	PLL2	PLL3	PLL4	PLL7	PLL8	PLL9	PLL10
1,020-pin FineLine BGA	Transmitter (4)	80 (12) (7)	840	12 (2)	10 (4)	10 (4)	12 (2)	20	20	20	20
			840 (5), (8)	22 (6)	22 (6)	22 (6)	22 (6)	20	20	20	20
	Receiver	80 (10) (7)	840	20	20	20	20	12 (8)	10 (10)	10 (10)	12 (8)
			840 (5), (8)	40	40	40	40	12 (8)	10 (10)	10 (10)	12 (8)
1,508-pin FineLine BGA	Transmitter (4)	80 (36) (7)	840	12 (8)	10 (10)	10 (10)	12 (8)	20	20	20	20
			840 (5), (8)	22 (18)	22 (18)	22 (18)	22 (18)	20	20	20	20
	Receiver	80 (36) (7)	840	20	20	20	20	12 (8)	10 (10)	10 (10)	12 (8)
			840 (5), (8)	40	40	40	40	12 (8)	10 (10)	10 (10)	12 (8)

Table 2–41. EP1S80 Differential Channels (Part 1 of 2) Note (1)

Package	Transmitter/ Receiver	Total Channels	Maximum Speed (Mbps)	Center Fast PLLs				Corner Fast PLLs (2), (3)			
				PLL1	PLL2	PLL3	PLL4	PLL7	PLL8	PLL9	PLL10
956-pin BGA	Transmitter (4)	80 (40) (7)	840	10	10	10	10	20	20	20	20
			840 (5), (8)	20	20	20	20	20	20	20	20
	Receiver	80	840	20	20	20	20	10	10	10	10
			840 (5), (8)	40	40	40	40	10	10	10	10
1,020-pin FineLine BGA	Transmitter (4)	92 (12) (7)	840	10 (2)	10 (4)	10 (4)	10 (2)	20	20	20	20
			840 (5), (8)	20 (6)	20 (6)	20 (6)	20 (6)	20	20	20	20
	Receiver	90 (10) (7)	840	20	20	20	20	10 (2)	10 (3)	10 (3)	10 (2)
			840 (5), (8)	40	40	40	40	10 (2)	10 (3)	10 (3)	10 (2)

The Quartus II MegaWizard® Plug-In Manager only allows the implementation of up to 20 receiver or 20 transmitter channels for each fast PLL. These channels operate at up to 840 Mbps. The receiver and transmitter channels are interleaved such that each I/O bank on the left and right side of the device has one receiver channel and one transmitter channel per LAB row. [Figure 2-74](#) shows the fast PLL and channel layout in EP1S10, EP1S20, and EP1S25 devices. [Figure 2-75](#) shows the fast PLL and channel layout in the EP1S30 to EP1S80 devices.

Figure 2-74. Fast PLL & Channel Layout in the EP1S10, EP1S20 or EP1S25 Devices *Note (1)*



Notes to Figure 2-74:

- (1) Wire-bond packages support up to 624 Mbps.
- (2) See [Table 2-41](#) for the number of channels each device supports.
- (3) There is a multiplexer here to select the PLL clock source. If a PLL uses this multiplexer to clock channels outside of its bank quadrant, those clocked channels support up to 840 Mbps for “high” speed channels and 462 Mbps for “low” speed channels, as labeled in the device pin-outs at www.altera.com.

Table 4–63. EP1S20 External I/O Timing on Column Pins Using Global Clock Networks *Note (1)*

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{INSU}	1.351		1.479		1.699		NA		ns
t_{INH}	0.000		0.000		0.000		NA		ns
t_{OUTCO}	2.732	5.380	2.732	5.728	2.732	6.240	NA	NA	ns
t_{XZ}	2.672	5.254	2.672	5.596	2.672	6.116	NA	NA	ns
t_{ZX}	2.672	5.254	2.672	5.596	2.672	6.116	NA	NA	ns
t_{INSUPLL}	0.923		0.971		1.098		NA		ns
t_{INHPLL}	0.000		0.000		0.000		NA		ns
t_{OUTCOPLL}	1.210	2.544	1.210	2.648	1.210	2.715	NA	NA	ns
t_{XZPLL}	1.150	2.418	1.150	2.516	1.150	2.591	NA	NA	ns
t_{ZXPLL}	1.150	2.418	1.150	2.516	1.150	2.591	NA	NA	ns

Table 4–64. EP1S20 External I/O Timing on Row Pins Using Fast Regional Clock Networks *Note (1)*

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{INSU}	2.032		2.207		2.535		NA		ns
t_{INH}	0.000		0.000		0.000		NA		ns
t_{OUTCO}	2.492	5.018	2.492	5.355	2.492	5.793	NA	NA	ns
t_{XZ}	2.519	5.072	2.519	5.411	2.519	5.861	NA	NA	ns
t_{ZX}	2.519	5.072	2.519	5.411	2.519	5.861	NA	NA	ns

Table 4–110. Stratix IOE Programmable Delays on Row Pins *Note (1)*

Parameter	Setting	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
Decrease input delay to internal cells	Off		3,970		4,367		5,022		5,908	ps
	Small		3,390		3,729		4,288		5,045	ps
	Medium		2,810		3,091		3,554		4,181	ps
	Large		173		181		208		245	ps
	On		173		181		208		245	ps
Decrease input delay to input register	Off		3,900		4,290		4,933		5,804	ps
	On		0		0		0		0	ps
Decrease input delay to output register	Off		1,240		1,364		1,568		1,845	ps
	On		0		0		0		0	ps
Increase delay to output pin	Off		0		0		0		0	ps
	On		397		417		417		417	ps
Increase delay to output enable pin	Off		0		0		0		0	ps
	On		348		383		441		518	ps
Increase output clock enable delay	Off		0		0		0		0	ps
	Small		180		198		227		267	ps
	Large		260		286		328		386	ps
	On		260		286		328		386	ps
Increase input clock enable delay	Off		0		0		0		0	ps
	Small		180		198		227		267	ps
	Large		260		286		328		386	ps
	On		260		286		328		386	ps
Increase output enable clock enable delay	Off		0		0		0		0	ps
	Small		540		594		683		804	ps
	Large		1,016		1,118		1,285		1,512	ps
	On		1,016		1,118		1,285		1,512	ps
Increase t_{ZX} delay to output pin	Off		0		0		0		0	ps
	On		1,993		2,092		2,092		2,092	ps

Note to Table 4–109 and Table 4–110:

- (1) The delay chain delays vary for different device densities. These timing values only apply to EP1S30 and EP1S40 devices. Reference the timing information reported by the Quartus II software for other devices.

Maximum Input & Output Clock Rates

Tables 4–114 through 4–119 show the maximum input clock rate for column and row pins in Stratix devices.

<i>Table 4–114. Stratix Maximum Input Clock Rate for CLK[7..4] & CLK[15..12] Pins in Flip-Chip Packages (Part 1 of 2)</i>					
I/O Standard	-5 Speed Grade	-6 Speed Grade	-7 Speed Grade	-8 Speed Grade	Unit
LVTTL	422	422	390	390	MHz
2.5 V	422	422	390	390	MHz
1.8 V	422	422	390	390	MHz
1.5 V	422	422	390	390	MHz
LVC MOS	422	422	390	390	MHz
GTL	300	250	200	200	MHz
GTL+	300	250	200	200	MHz
SSTL-3 Class I	400	350	300	300	MHz
SSTL-3 Class II	400	350	300	300	MHz
SSTL-2 Class I	400	350	300	300	MHz
SSTL-2 Class II	400	350	300	300	MHz
SSTL-18 Class I	400	350	300	300	MHz
SSTL-18 Class II	400	350	300	300	MHz
1.5-V HSTL Class I	400	350	300	300	MHz
1.5-V HSTL Class II	400	350	300	300	MHz
1.8-V HSTL Class I	400	350	300	300	MHz
1.8-V HSTL Class II	400	350	300	300	MHz
3.3-V PCI	422	422	390	390	MHz
3.3-V PCI-X 1.0	422	422	390	390	MHz
Compact PCI	422	422	390	390	MHz
AGP 1×	422	422	390	390	MHz
AGP 2×	422	422	390	390	MHz
CTT	300	250	200	200	MHz
Differential 1.5-V HSTL C1	400	350	300	300	MHz
LVPECL (1)	645	645	622	622	MHz
PCML (1)	300	275	275	275	MHz

Table 4–118. Stratix Maximum Input Clock Rate for CLK[0, 2, 9, 11] Pins & FPLL[10..7]CLK Pins in Wire-Bond Packages (Part 2 of 2)

I/O Standard	-6 Speed Grade	-7 Speed Grade	-8 Speed Grade	Unit
LVC MOS	422	390	390	MHz
GTL+	250	200	200	MHz
SSTL-3 Class I	350	300	300	MHz
SSTL-3 Class II	350	300	300	MHz
SSTL-2 Class I	350	300	300	MHz
SSTL-2 Class II	350	300	300	MHz
SSTL-18 Class I	350	300	300	MHz
SSTL-18 Class II	350	300	300	MHz
1.5-V HSTL Class I	350	300	300	MHz
1.8-V HSTL Class I	350	300	300	MHz
CTT	250	200	200	MHz
Differential 1.5-V HSTL C1	350	300	300	MHz
LVPECL (1)	717	640	640	MHz
PCML (1)	375	350	350	MHz
LVDS (1)	717	640	640	MHz
HyperTransport technology (1)	717	640	640	MHz

Table 4–119. Stratix Maximum Input Clock Rate for CLK[1, 3, 8, 10] Pins in Wire-Bond Packages (Part 1 of 2)

I/O Standard	-6 Speed Grade	-7 Speed Grade	-8 Speed Grade	Unit
LVTTL	422	390	390	MHz
2.5 V	422	390	390	MHz
1.8 V	422	390	390	MHz
1.5 V	422	390	390	MHz
LVC MOS	422	390	390	MHz
GTL+	250	200	200	MHz
SSTL-3 Class I	350	300	300	MHz
SSTL-3 Class II	350	300	300	MHz
SSTL-2 Class I	350	300	300	MHz
SSTL-2 Class II	350	300	300	MHz

Table 4–122. Stratix Maximum Output Clock Rate for PLL[5, 6, 11, 12] Pins in Wire-Bond Packages (Part 2 of 2)

I/O Standard	-6 Speed Grade	-7 Speed Grade	-8 Speed Grade	Unit
LVDS (2)	311	275	275	MHz
HyperTransport technology (2)	311	275	275	MHz

Table 4–123. Stratix Maximum Output Clock Rate (Using I/O Pins) for PLL[1, 2, 3, 4] Pins in Wire-Bond Packages (Part 1 of 2)

I/O Standard	-6 Speed Grade	-7 Speed Grade	-8 Speed Grade	Unit
LVTTTL	200	175	175	MHz
2.5 V	200	175	175	MHz
1.8 V	200	175	175	MHz
1.5 V	200	175	175	MHz
LVC MOS	200	175	175	MHz
GTL	125	100	100	MHz
GTL+	125	100	100	MHz
SSTL-3 Class I	110	90	90	MHz
SSTL-3 Class II	150	133	133	MHz
SSTL-2 Class I	90	80	80	MHz
SSTL-2 Class II	110	100	100	MHz
SSTL-18 Class I	110	100	100	MHz
SSTL-18 Class II	110	100	100	MHz
1.5-V HSTL Class I	225	200	200	MHz
1.5-V HSTL Class II	200	167	167	MHz
1.8-V HSTL Class I	225	200	200	MHz
1.8-V HSTL Class II	200	167	167	MHz
3.3-V PCI	200	175	175	MHz
3.3-V PCI-X 1.0	200	175	175	MHz
Compact PCI	200	175	175	MHz
AGP 1×	200	175	175	MHz
AGP 2×	200	175	175	MHz
CTT	125	100	100	MHz
LVPECL (2)	311	270	270	MHz
PCML (2)	400	311	311	MHz

Table 4–129. Enhanced PLL Specifications for -7 Speed Grade (Part 2 of 2)

Symbol	Parameter	Min	Typ	Max	Unit
t_{OUTDUTY}	Duty cycle for external clock output (when set to 50%)	45		55	%
t_{JITTER}	Period jitter for external clock output (6)			± 100 ps for >200-MHz outclk ± 20 mUI for <200-MHz outclk	ps or mUI
$t_{\text{CONFIG5,6}}$	Time required to reconfigure the scan chains for PLLs 5 and 6			$289/f_{\text{SCANCLK}}$	
$t_{\text{CONFIG11,12}}$	Time required to reconfigure the scan chains for PLLs 11 and 12			$193/f_{\text{SCANCLK}}$	
t_{SCANCLK}	scanclk frequency (5)			22	MHz
t_{DLOCK}	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays) (7) (11)	(9)		100	μs
t_{LOCK}	Time required to lock from end of device configuration (11)	10		400	μs
f_{VCO}	PLL internal VCO operating range	300		600 (8)	MHz
t_{LSKEW}	Clock skew between two external clock outputs driven by the same counter		± 50		ps
t_{SKEW}	Clock skew between two external clock outputs driven by the different counters with the same settings		± 75		ps
f_{SS}	Spread spectrum modulation frequency	30		150	kHz
% spread	Percentage spread for spread spectrum frequency (10)	0.5		0.6	%
t_{ARESET}	Minimum pulse width on areset signal	10			ns

Table 4–130. Enhanced PLL Specifications for -8 Speed Grade (Part 1 of 3)

Symbol	Parameter	Min	Typ	Max	Unit
f_{IN}	Input clock frequency	3 (1), (2)		480	MHz
f_{INPFD}	Input frequency to PFD	3		420	MHz
f_{INDUTY}	Input clock duty cycle	40		60	%
f_{EINDUTY}	External feedback clock input duty cycle	40		60	%
t_{INJITTER}	Input clock period jitter			± 200 (3)	ps



5. Reference & Ordering Information

S51005-2.1

Software

Stratix® devices are supported by the Altera® Quartus® II design software, which provides a comprehensive environment for system-on-a-programmable-chip (SOPC) design. The Quartus II software includes HDL and schematic design entry, compilation and logic synthesis, full simulation and advanced timing analysis, SignalTap® II logic analyzer, and device configuration. See the *Design Software Selector Guide* for more details on the Quartus II software features.

The Quartus II software supports the Windows XP/2000/NT/98, Sun Solaris, Linux Red Hat v7.1 and HP-UX operating systems. It also supports seamless integration with industry-leading EDA tools through the NativeLink® interface.

Device Pin-Outs

Stratix device pin-outs can be found on the Altera web site (www.altera.com).

Ordering Information

Figure 5–1 describes the ordering codes for Stratix devices. For more information on a specific package, see the *Package Information for Stratix Devices* chapter.